

<b>Notice of References Cited</b>	Application/Control No. 09/772,621	Applicant(s)/Patent Under Reexamination WENDEL RUP, HEINO	
	Examiner Sharad Rampuria	Art Unit 2683	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,157,844 A	12-2000	Doran et al.	455/552.1
	B	US-6,195,568 B1	02-2001	Irvin, David R.	455/563
	C	US-4,961,212	10-1990	Marui et al.	379/88.03
	D	US-6,690,954 B2	02-2004	Ushida, Bunji	455/563
	E	US-6,377,820 B1	04-2002	Courtis et al.	455/563
	F	US-6,577,881 B1	06-2003	Ehara, Tatsuji	455/563
	G	US-6,393,305 B1	05-2002	Ulvinen et al.	455/563
	H	US-6,349,222 B1	02-2002	Hafiz, Sheikh A.	455/569.2
	I	US-6,263,216 B1	07-2001	Seydoux et al.	455/564
	J	US-6,212,408 B1	04-2001	Son et al.	455/563
	K	US-6,157,848 A	12-2000	Bareis et al.	455/563
	L	US-5,148,471 A	09-1992	Metroka et al.	455/563
	M	US-5,335,276 A	08-1994	Thompson et al.	380/266

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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